Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/624,403	FU ET AL.	
Examiner	Art Unit	
Shin-Hon Chen	2131	

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USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - see search history)	3/29/2007	S.C.
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